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# Author Correction: A quantitative approach for trap analysis between $\text{Al}_{0.25}\text{Ga}_{0.75}\text{N}$ and GaN in high electron mobility transistors

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The original version of this Article contained an error in the Acknowledgments section.

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now reads:

“This work was supported by a National Research Foundation of Korea (NRF) grant funded by the Korean government (MSIP; Ministry of Science, ICT and Future Planning, NRF- 2019R1A2C1009816 and NRF-2019M3F5A1A01076973).”

The original Article has been corrected.



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